

EWS Factsheet



EWS Rhode Island
Department
of Education
Early Warning System

What is an Early Warning System?

An Early Warning System (EWS) uses indicators to identify students at risk of not graduating high school on time. School districts nationally are utilizing Early Warning Systems to enable data-driven decision making to improve the success of students and schools.

Why do school districts need an EWS?

- Nationally, **25%** of all high school students leave the public school system **before graduating**.
- **23 %** of high school students **in Rhode Island** leave before graduating.
- **33%** of **minority** high school students **in Rhode Island** leave before graduating.
- State regulations require that schools use an early warning system to track students in grades 6-12 progress to on-time graduation.

How does an Early Warning System support students and schools?

- Early warning systems use data that are readily available at schools.
- EWS indicators are better predictors of on time graduation than background characteristics or stand-alone achievement test scores.
- Attendance percentages in the first month, first-quarter, and first semester of school are the strongest predictors of on time graduation. These data are available early in the school year.

The Rhode Island Early Warning System

The Rhode Island EWS is modeled on seven years of historical student data in Rhode Island. The Rhode Island EWS is made up of the following indicators for each student in grades 6-12:

- **Attendance Percentage**
The number of days a student is present at school in a given school year.
- **Number of Suspensions**
The count of the number of suspensions accumulated by a student over a school year.
- **Years Over-age**
The number of years a student is older than the standard age for a given grade.
- **Aggregate On Time Graduation Indicator**
The likelihood of a student graduating on time if they stay on their current path.
- **NECAP Reading and Math Scores**
The scaled score a student received in the most recent testing year.